

February 2007

# **FDMC8854**

# N-Channel Power Trench® MOSFET

**30V**, **15A**, **5.7m**Ω

### **Features**

- Max  $r_{DS(on)} = 5.7 m\Omega$  at  $V_{GS} = 10 V$ ,  $I_D = 15 A$
- Max  $r_{DS(on)} = 7.6 \text{m}\Omega$  at  $V_{GS} = 4.5 \text{V}$ ,  $I_D = 13 \text{A}$
- Low Profile 1mm max in Power 33
- RoHS Compliant



# **General Description**

This N-Channel MOSFET is a rugged gate version of Fairchild Semiconductor's advanced Power Trench process. It has been optimized for power management applications.

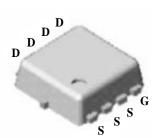
# **Application**

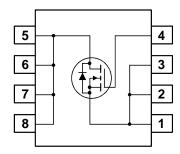
■ DC - DC Conversion

#### **Bottom**



### Top





Power 33

# MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
$V_{DS}$	Drain to Source Voltage			30	V
$V_{GS}$	Gate to Source Voltage			±20	V
	Drain Current -Continuous (Package limited)	$T_C = 25^{\circ}C$		15	
	-Continuous (Silicon limited)	$T_C = 25^{\circ}C$		67	^
ID	-Continuous	T <sub>A</sub> = 25°C	(Note 1a)	15	Α
	-Pulsed			30	
D	Power Dissipation	$T_C = 25^{\circ}C$		41	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1a)	2.0	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case		3	°C/M
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	60	°C/W

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC8854	FDMC8854	Power 33	7"	8mm	3000 units

# **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
$BV_DSS$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , referenced to 25°C		21		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24V,  V_{GS} = 0V$			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{GS} = 0V$			±100	nA

## On Characteristics (Note 2)

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1	1.9	3	٧
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , referenced to 25°C		-6		mV/°C
	r <sub>DS(on)</sub> Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 15A$		4.4	5.7	
r <sub>DS(on)</sub>		$V_{GS} = 4.5V, I_D = 13A$		5.6	7.6	mΩ
	$V_{GS} = 10V, I_D = 15A, T_J = 125^{\circ}C$		6.6	9.0		
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5V, I_{D} = 15A$		60		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	101/1/	2560	3405	pF
Coss	Output Capacitance	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 0V, f = 1MHz	515	685	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1101112	290	435	pF
$R_g$	Gate Resistance	f = 1MHz	1.3		Ω

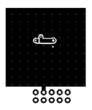
## **Switching Characteristics**

	•				
t <sub>d(on)</sub>	Turn-On Delay Time	.,	13	23	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 10V, I_{D} = 15A$ $V_{GS} = 10V, R_{GEN} = 6\Omega$	5	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 602$	31	50	ns
t <sub>f</sub>	Fall Time		5	10	ns
$Q_{g(TOT)}$	Total Gate Charge	V 40V L 45A	41	57	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DD} = 10V, I_D = 15A,$ $V_{GS} = 10V$	7		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V	7		nC

## **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 15A$ (Note 2)		0.8	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	1 - 15 \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \		33	50	ns
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = 15A, di/dt = 100A/μs		28	42	nC

<sup>1:</sup> R<sub>BJA</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>BJC</sub> is guaranteed by design while R<sub>BCA</sub> is determined by the user's board design.



a. 60°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper

b. 135°C/W when mounted on a minimum pad of 2 oz copper



2: Pulse Test: Pulse Width <  $300\mu$ s, Duty cycle < 2.0%.

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

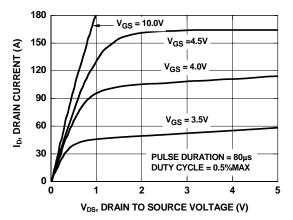


Figure 1. On-Region Characteristics

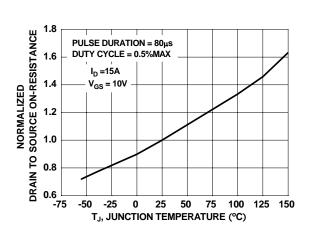


Figure 3. Normalized On-Resistance vs Junction Temperature

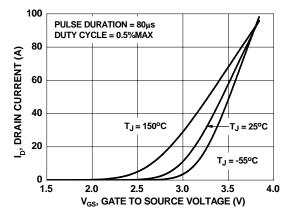


Figure 5. Transfer Characteristics

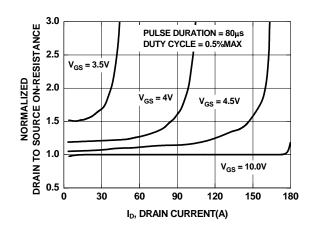


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

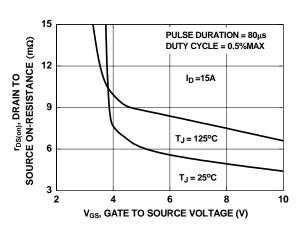


Figure 4. On-Resistance vs Gate to Source Voltage

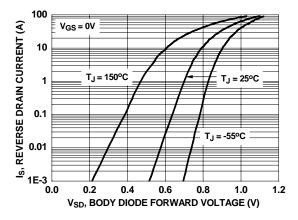


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

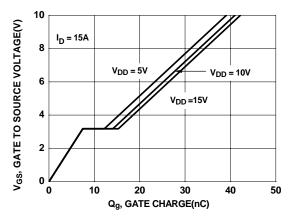


Figure 7. Gate Charge Characteristics

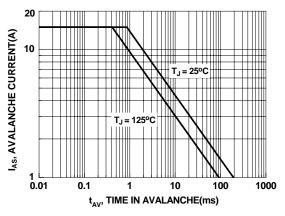


Figure 9. Unclamped Inductive Switching Capability

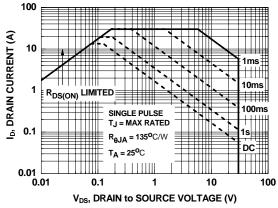


Figure 11. Forward Bias Safe Operating Area

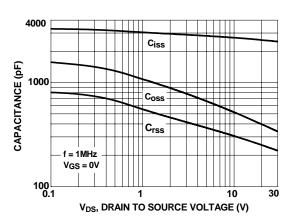


Figure 8. Capacitance vs Drain to Source Voltage

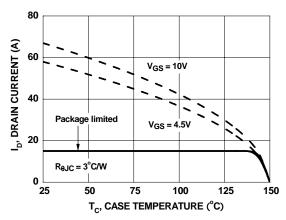


Figure 10. Maximum Continuous Drain Current vs Case Temperature

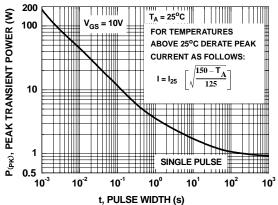


Figure 12. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted

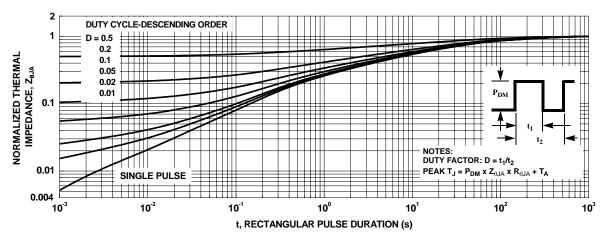
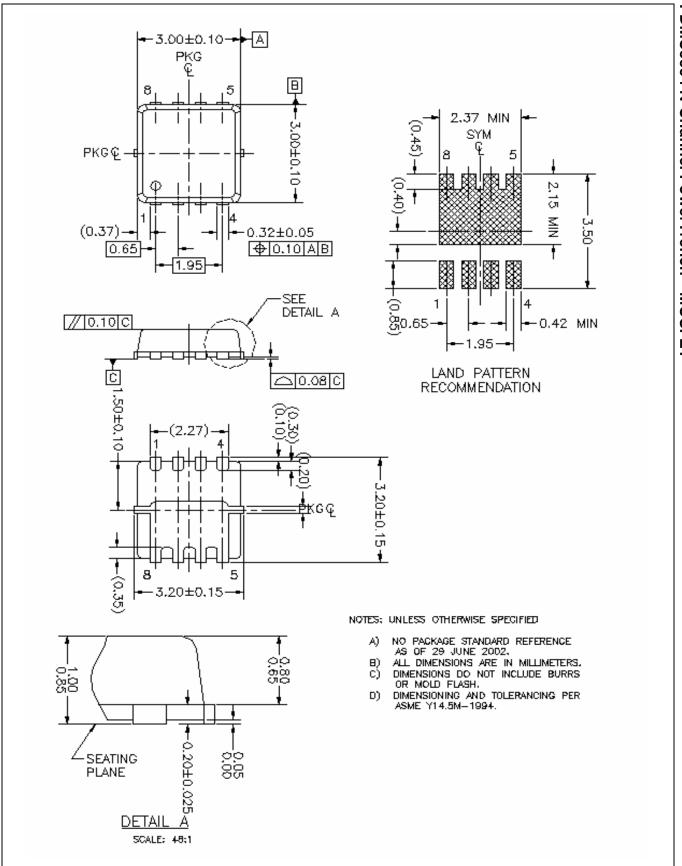


Figure 13. Transient Thermal Response Curve



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